

L	Number	Hits	Search Text	DB	Time stamp
1	1	5	"6025600"	USPAT; US-PGPUB; EPO; JPO; DEFWENT; IBM_TDB	2003/02/05 12:32
2	2	3210	250/396R	USPAT; US-PGPUB; EPO; JPO; DEFWENT; IBM_TDB	2003/02/05 12:32
3	3	10	("4162403" "4180738" "4554452" "4567369" "5047646" "5144129" "5362829" "5313062" "5396077" "5617373").PN.	USPAT	2003/02/05 12:31
4	4	6	5047646.URPN.	USPAT	2003/02/05 12:31
5	5	3	5302829.URPN.	USPAT	2003/02/05 12:31
6	6	6	("4695725" "4818873" "5047646" "5134288" "5144129" "5654547").PN.	USPAT	2003/02/05 12:31
-	-	50638	(electron adj microscope) or (charged adj particle)	USPAT; US-PGPUB; EPO; JPO; DEFWENT; IBM_TDB	2003/02/01 16:51
-	-	43956	(electron adj microscope) or (charged adj particle adj beam)	USPAT; US-PGPUB; EPO; JPO; DEFWENT; IBM_TDB	2003/02/01 16:51
-	-	646	((electron adj microscope) or (charged adj particle adj beam)) and (astigmatism)	USPAT; US-PGPUB; EPO; JPO; DEFWENT; IBM_TDB	2003/02/03 14:41
-	-	840	250/305	USPAT; US-PGPUB; EPO; JPO; DEFWENT; IBM_TDB	2003/02/01 17:02
-	-	2627	250/306	USPAT; US-PGPUB; EPO; JPO; DEFWENT; IBM_TDB	2003/02/01 17:03
-	-	1936	250/307	USPAT; US-PGPUB; EPO; JPO; DEFWENT; IBM_TDB	2003/02/01 17:04
-	-	677	250/308	USPAT; US-PGPUB; EPO; JPO; DEFWENT; IBM_TDB	2003/02/01 17:04
-	-	822	250/309	USPAT; US-PGPUB; EPO; JPO; DEFWENT; IBM_TDB	2003/02/01 17:05
-	-	2167	250/310	USPAT; US-PGPUB; EPO; JPO; DEFWENT; IBM_TDB	2003/02/01 17:06

3171 250/311

USPAT; 2003/02/01
US-PGPUB; 17:07
EPO; JPO;
DERWENT;
IBM_TDB

1022 250/396ML

USPAT; 2003/02/01
US-PGPUB; 17:08
EPO; JPO;
DERWENT;
IBM_TDB

1570 250/398

USPAT; 2003/02/01
US-PGPUB; 17:09
EPO; JPO;
DERWENT;
IBM_TDB

2372 250/492.1

USPAT; 2003/02/01
US-PGPUB; 17:11
EPO; JPO;
DERWENT;
IBM_TDB

4131 250/492.2

USPAT; 2003/02/01
US-PGPUB; 17:13
EPO; JPO;
DERWENT;
IBM_TDB

144726 watanabe.in.

USPAT; 2003/02/01
US-PGPUB; 17:13
EPO; JPO;
DERWENT;
IBM_TDB

376 watanabe.in. and (astigmatism or
(scanning adj electron adj microscope))

USPAT; 2003/02/03
US-PGPUB; 14:41
EPO; JPO;
DERWENT;
IBM_TDB

274 (((electron adj microscope) or (charged
adj particle adj beam)) and
(astigmatism)) and focal

USPAT; 2003/02/03
US-PGPUB; 14:49
EPO; JPO;
DERWENT;
IBM_TDB

351 (((electron adj microscope) or (charged
adj particle adj beam)) and
(astigmatism)) and focus

USPAT; 2003/02/04
US-PGPUB; 10:17
EPO; JPO;
DERWENT;
IBM_TDB

219 250/49\$3 and diagonal

USPAT; 2003/02/05
US-PGPUB; 08:55
EPO; JPO;
DERWENT;
IBM_TDB

514 250/3\$2 and diagonal

USPAT; 2003/02/05
US-PGPUB; 08:56
EPO; JPO;
DERWENT;
IBM_TDB